Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/678,633	LEE ET AL.	
Examiner	**Art Unit**	
TAN X. DINH	2627	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (see search history printout)	5/30/2007	T.D